FOR IMMEDIATE RELEASE

Aehr Test Systems
Carl Buck
Vice President of Marketing
(510) 623-9400 x381

Investor Relations Contact:
Todd Kehrli or Jim Byers
MKR Group, Inc.
(323) 468-2300
aehr@mkr-group.com

Aehr Test Systems Announces $4 Million Order for Multiple ABTS™ Burn-in and Test Systems from Leading IC Manufacturer

Fremont, CA (July 26, 2016) – Aehr Test Systems (NASDAQ: AEHR), a worldwide supplier of semiconductor test and burn-in equipment, today announced that it has received $4 million in follow-on orders for its Advanced Burn-in and Test Systems (ABTS) from a leading multi-national manufacturer of advanced logic integrated circuits (ICs) for automotive, embedded processing, digital signal processing and analog applications. The orders include significant prepayments to lock in short lead times and special pricing. The systems are expected to ship over the first three quarters of Aehr Test's fiscal 2017.

Gayn Erickson, President and CEO of Aehr Test Systems, commented, "We are very pleased to receive these follow-on orders for additional ABTS systems from this major semi-conductor customer. This is encouraging for our base business, which has been soft for the last few quarters."

"The customer is running at full capacity in their production burn-in area and needed to add capacity both to satisfy increasing demand for existing products and for products that are just beginning their production ramp," said Mark Allison, Vice President of Sales at Aehr. "Two configurations of the ABTS system were ordered. The ABTS-P configuration is targeted at production test and burn-in of lower-power devices and offers compatibility with the customer's extensive inventory of burn-in boards for our previous MAX™ family of test and burn-in systems. This configuration also allows customers to transition easily from their legacy MAX systems to the enhanced per-pin architecture and higher channel count of the ABTS-P system, key capabilities required for burn-in and test of the latest ICs. The ABTS-Li configuration features individual device temperature control for improved thermal control of higher-power devices, which is needed for sophisticated processors fabricated with state-of-the-art processes. The customer's devices are used for embedded processing and integrated analog devices, many of them for the growing automotive advanced driver assistance market."

The ABTS family of products is based on a state-of-the-art hardware and software platform that is designed to address not only today's devices, but also future devices for many years to come. It can test and burn-in both logic and memory devices and includes resources for high pin-count devices and configurations for high-power and low-power applications. ABTS systems can be configured with up to 72 burn-in boards, up to 320 I/O channels, 32M of test vector memory per channel and up to 16 independent device power supplies. The ABTS

system can be configured with a scalable cost-effective individual device temperature control solution for up to 64 devices per burn-in board and up to 75 watts per device or more. Individual temperature control enables high-power devices with a broad range of power dissipation to be burned-in simultaneously in a single burn-in chamber while maintaining a precise device temperature. The ABTS system also uses N+1 redundancy technology for many key components in the system to maximize system uptime.

About Aehr Test Systems

Headquartered in Fremont, California, Aehr Test Systems is a worldwide provider of test systems for burning-in and testing logic and memory integrated circuits and has an installed base of more than 2,500 systems worldwide. Increased quality and reliability needs of the Automotive and Mobility integrated circuit markets are driving additional test requirements, capacity needs and opportunities for Aehr Test products in package and wafer level test. Aehr Test has developed and introduced several innovative products, including the ABTS™ and FOX families of test and burn-in systems and the DiePak® carrier. The ABTS system is used in production and qualification testing of packaged parts for both lower-power and higher-power logic as well as all common types of memory devices. The FOX system is a full wafer contact test and burn-in system used for burn-in and functional test of complex devices, such as leading-edge memories, digital signal processors, microprocessors, microcontrollers and systems-on-a-chip. The DiePak carrier is a reusable, temporary package that enables IC manufacturers to perform cost-effective final test and burn-in of bare die. For more information, please visit the Company's website at www.aehr.com.

Safe Harbor Statement

This press release contains certain forward-looking statements based on current expectations, forecasts and assumptions that involve risks and uncertainties. These statements are based on information available to Aehr Test as of the date hereof and actual results could differ materially from those stated or implied due to risks and uncertainties. Forward-looking statements include statements regarding expected shipping dates of our ABTS systems and uses of our ABTS systems. The risks and uncertainties that could cause our results to differ materially from those expressed or implied by such forward-looking statements include, without limitation, general world economic conditions and events, the state of the semiconductor equipment market, our ability to maintain sufficient cash to support operations, acceptance by customers of the ABTS technology, acceptance by customers of the ABTS systems shipped upon receipt of a purchase order and the ability of new products to meet customer needs or perform as described. See Aehr Test's recent 10-K, 10-Q and other reports from time to time filed with the Securities and Exchange Commission for a more detailed description of the risks facing Aehr Test's business. Aehr Test disclaims any obligation to update information contained in any forward-looking statement to reflect events or circumstances occurring after the date of this press release.

# # #